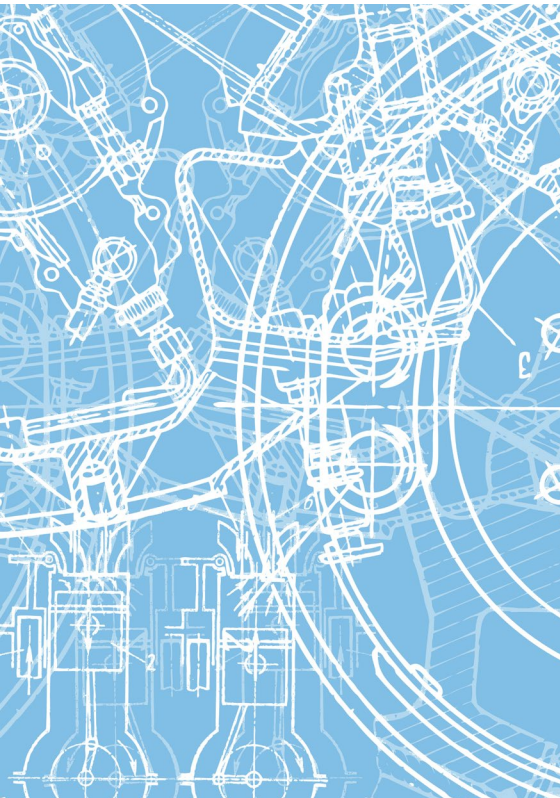




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Metrology



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Message from the Editor-in-Chief

Metrology draws together researchers from diverse areas of metrology or measurement technology in a wide variety of applications. I encourage you to submit your manuscripts for consideration or publication in the area of measurement engineering, according to the scope of the journal. *Metrology* is supported by our authors and their institutes through low article processing charges (APC) for accepted papers. We hope you will support the journal by becoming one of our authors.

Editor-in-Chief

Prof. Dr. Han Haitjema

Aims

Metrology (ISSN 2673-8244) is an international, peer-reviewed, open access journal that provides an advanced forum for articles covering theory, design, and application in measurement science or measurement technology. *Metrology* publishes full research papers, communications, and review articles as well as Special Issues on particular subjects.

The aim of *Metrology* is to encourage scientists to publish their experimental and theoretical results in as much detail as possible. Therefore, the journal has no restrictions regarding the length of papers. Full experimental details should be provided so that the results can be reproduced.

Scope

- Traceability to SI units of complex measurement systems;
- Measurement theory in a broad context;
- Measurement uncertainty and uncertainty evaluation;
- Considerations on the fundamentals of measurement;
- Error separation methods;
- Novel methods inspired by the redefinition of the SI;
- Cyberphysical systems;
- Artificial intelligence, especially its effect on traceability;
- Machine learning for metrology;
- Precision measurement;
- Digital twins;
- Metrology for sustainable manufacturing;
- Precision manufacturing;
- Measurement techniques and devices;
- Interferometry;
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- 3D metrology;
- Frequency metrology;
- Surface metrology;
- Biomedical measurement;
- Virtual measurement;
- Power measurement.

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